Applicant(s)/Patent Under Application/Control No. Reexamination 10/694,787 LIN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2871 Tai Duong **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 06-2002 349/2 US-2002/0067440 Chino et al. 349/65 US-6,147,725 11-2000 Yuuki et al. В US-С US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 60-072493 04-1985 Japan Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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